

**Notice of References Cited**

Application/Control No.

10/724,921

Applicant(s)/Patent Under  
Reexamination  
KAWAGUCHI ET AL.

Examiner

Anil Khatri

Art Unit

2191

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,901,588	05-2005	Krapf et al.	717/164
*	B	US-6,546,546	04-2003	Van Doorn, Leendert Peter	717/114
*	C	US-6,795,864	09-2004	Connor, William H.	709/232
*	D	US-6,931,623	08-2005	Vermeire et al.	717/108
*	E	US-7,047,488	05-2006	Ingersoll et al.	715/523
*	F	US-6,324,543	11-2001	Cohen et al.	707/200
*	G	US-6,011,918	01-2000	Cohen et al.	717/106
*	H	US-5,953,526	09-1999	Day et al.	717/108
*	I	US-6,272,672	08-2001	Conway, Melvin E.	717/107
*	J	US-6,370,685	04-2002	Robison, Arch D.	717/141
*	K	US-6,745,384	06-2004	Biggerstaff, Ted J.	717/156
*	L	US-6,567,801	05-2003	Chiang et al.	707/3
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.